

Form PTO 1449  
US DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT

Applicant's Document No. 989\_001DIV1

Serial No. 10/004,463

Applicant James E. Moon et al.

Filing Date November 02, 2001

Group 1746

U.S. PATENT DOCUMENTS

Exam. Initial		Document Number	Date	Name	Class	Sub Class	Filing Date
<i>See</i>	AG	4,764,244	08/16/1998	Chitty et al.			06/11/1985
	AH	5,131,978	07/21/1992	O'Neill			06/07/1990
	AI	5,628,917	05/13/1997	MacDonald et al.			02/03/1995
	AJ	5,658,471	08/19/1997	Murthy et al.			09/22/1995
	AK	5,683,591	11/04/1997	Offenberg			11/27/1995
	AL	5,690,841	11/25/1997	Elderstig			06/10/1996
<i>See</i>	AM	5,717,251	02/10/1998	Hayashi et al.			08/05/1996

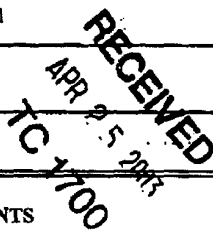
FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Sub Class	Translation	Abstract
<i>See</i>	AN	DE 44 42 023	05/30/1996	Germany				

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages Etc.)

<i>See</i>	AO	Desai, Amish, et al., <i>A MEMS Electro spray Nozzle for Mass Spectroscopy</i> , 1997, pp. 927-930.
	AP	Dole, Malcom, et al., <i>Molecular Beams of Macroions</i> , 1968, pp. 2240-2249.
	AQ	Harrison, D. Jed, et al., <i>Micromachining a Miniaturized Capillary Electrophoresis-Based Chemical Analysis System on a Chip</i> , 1993, pp. 895-897.
	AR	He, Bing, et al., <i>Fabrication of Nanocolumns for Liquid Chromatography</i> , 1998, pp. 3790-3797.
	AS	Jacobson, Stephen C., et al., <i>High-Speed Separations on a Microchip</i> , 1994, pp. 1114-1118.
	AT	Jacobson, Stephen C., et al., <i>Open channel Electrochromatography on a Microchip</i> , 1994, pp. 2369-2373.
	AU	Ramsey, R.S., et al., <i>Generating Electro spray from Microchip Devices Using Electroosmotic Pumping</i> , 1997, pp. 1174-1178.
	AV	Smith, David P., <i>The Electrohydrodynamic Atomization of Liquids</i> , 1986, pp. 527-535.
	AW	Wang, Xuan-Oi, et al., <i>Polymer-Based Electro spray Chips for Mass Spectrometry</i> , 1999, pp. 523-528.
	AX	Wilm, Mathias et al., <i>Analytical Properties of the Nanoelectrospray Ion Source</i> , 1996, pp. 1-8.
	AY	Xue, Gifeng, et al., <i>Multichannel Microchip Electro spray Mass Spectrometry</i> , 1997, pp. 426-430.
<i>See</i>	AZ	Yamashita, Masamichi, et al., <i>Electrospray Ion Source. Another Variation of the Free-Jet Theme</i> , 1984, pp. 4451-4459.

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*Allen Dole 9/29/02*

Form PTO 1449 US DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  INFORMATION DISCLOSURE STATEMENT BY APPLICANT	Atty Docket No. 989_001DIV1	Serial No.
	Applicant James E. Moon et al.	
	Filing Date	Group

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 10/004463  
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	AB	5,006,202	04/09/91	Hawkins et al.			
	AC	5,770,465	06/23/98	MacDonald et al.			
	AD	6,020,272	02/01/00	Fleming			
	AE	6,136,243	10/24/01	Mehregany et al.			
<i>AF</i>	AF	6,174,820	01/16/01	Habermehl et al.			

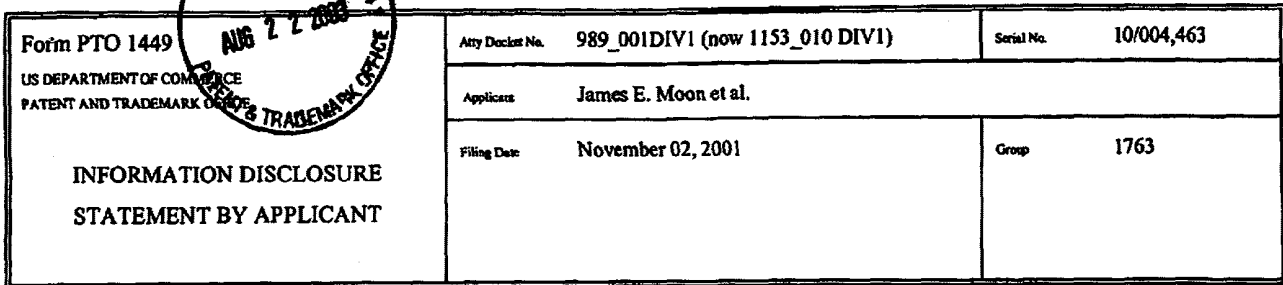
### FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Sub Class	Translation	Abstract

### OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages Etc.)

Examiner <i>Alta Olan</i>	Date Considered <i>9/29/03</i>

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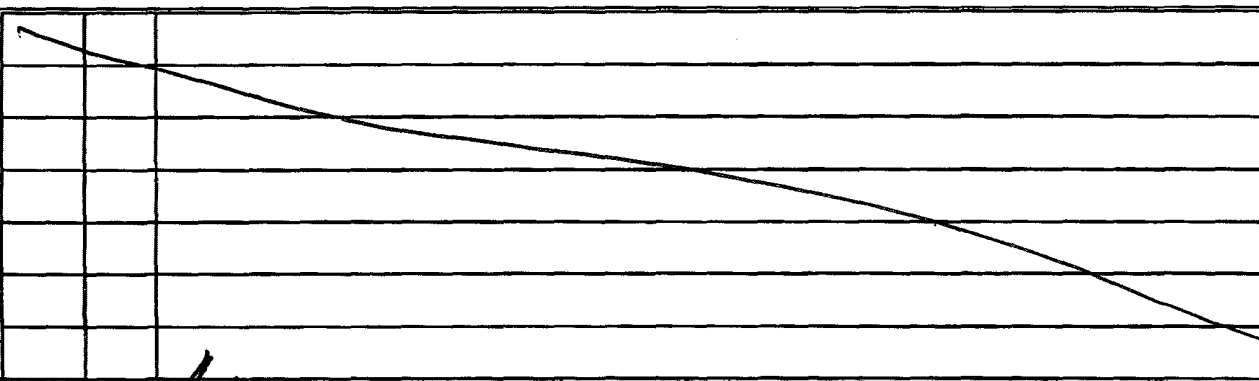
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<i>AS</i>	BA	5,043,043	08/27/1991	Howe et al.	_____	_____	06/22/1990
<i>AS</i>	BB	5,804,084	09/08/1998	Nasby et al.	_____	_____	10/11/1996
<i>AS</i>	BC	6,071,819	06/06/2000	Tai et al.	_____	_____	01/23/1998

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**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages Etc.)**

	
Examiner <i>Allen Oba</i>	Date Considered <i>9/29/03</i>

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